



## Wavefront sensors and adaptive optics for optical metrology, laser and microscopy



OPTICAL METROLOGY



HIGH-POWER LASERS



BIO-IMAGING



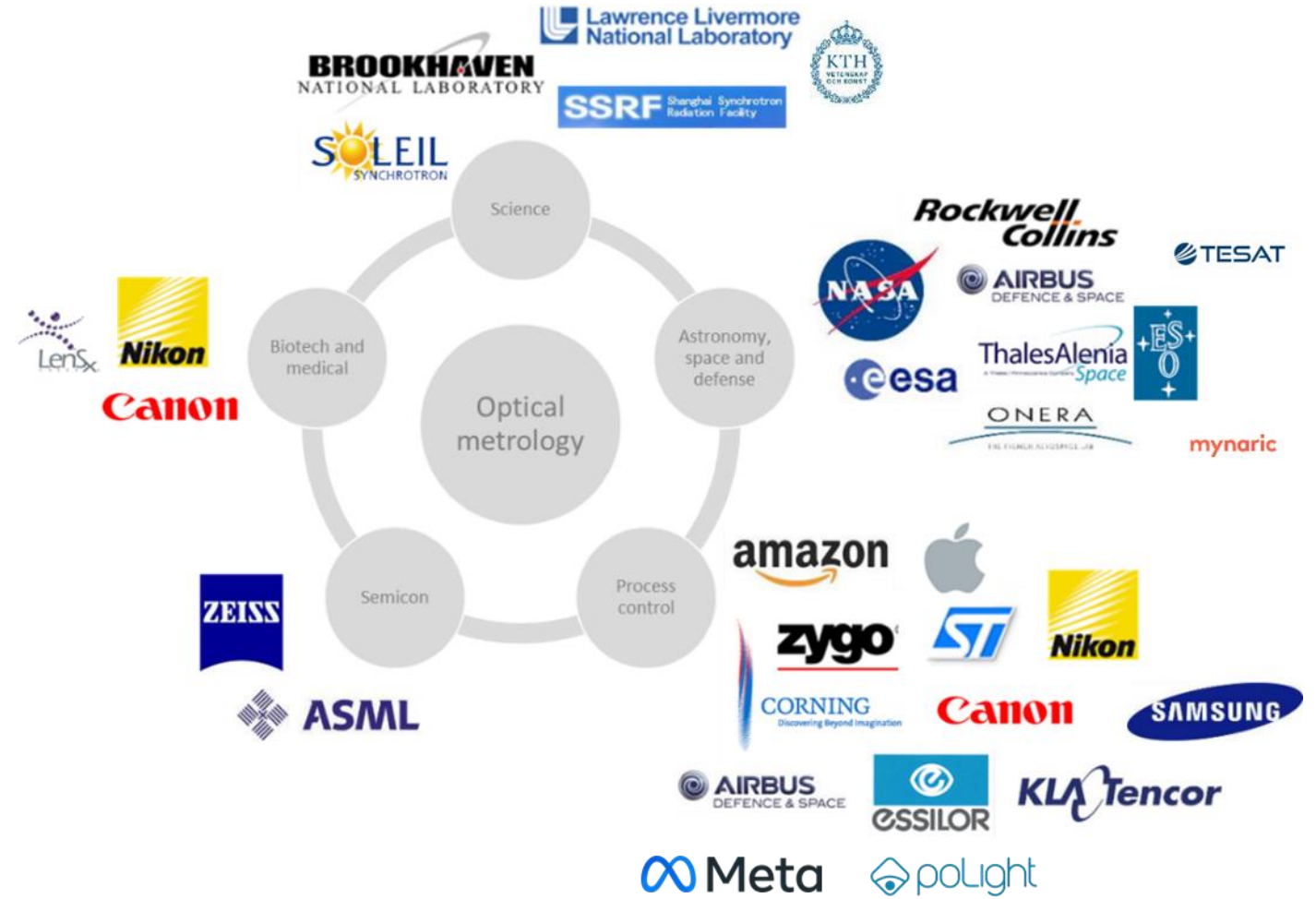
X-EUV



**IMAGINE OPTIC  
PRESENTS**

**New optical metrology system for plane parallel optics**

# Company · Key figures



## The OEC (The Optical Engineer Companion)



Modular system  
for lab and R&D

## MESO



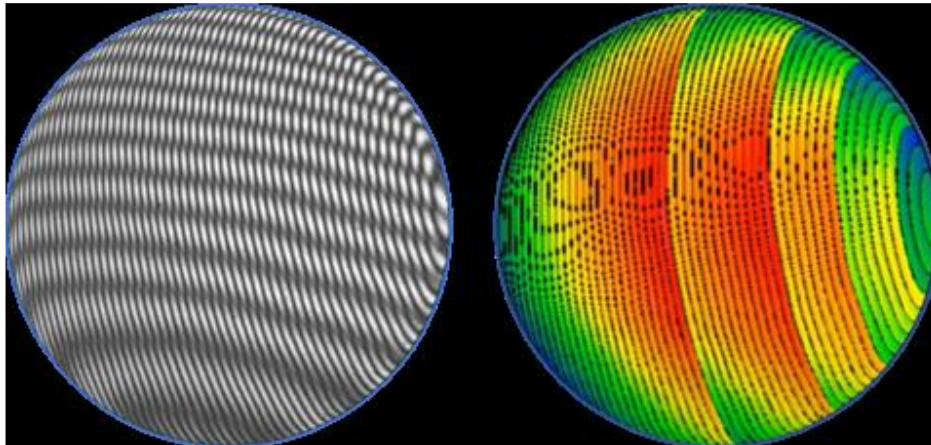
Robust instrument  
for industry and production



- + Insensitive to vibrations
- + At design wavelength testing from 400 to 800
- + Test diameter from 1,5" up to 6"
- + Insensitive to reflections from sample back surface



Std laser interferometer



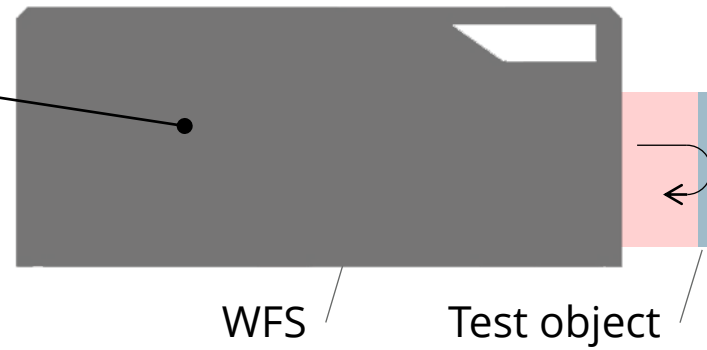
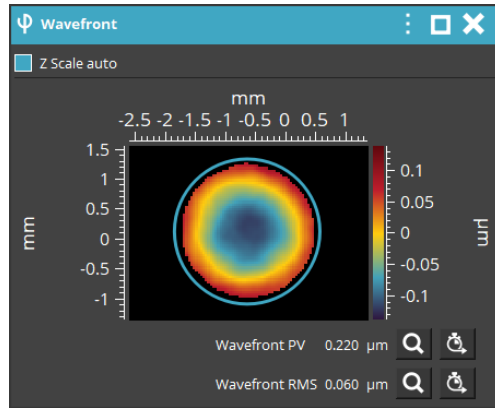
- 3 beams interference produced by a plane parallel optics

MESO

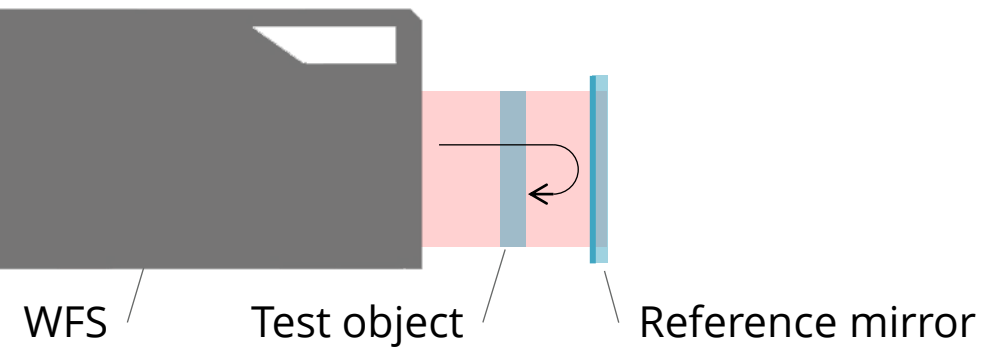
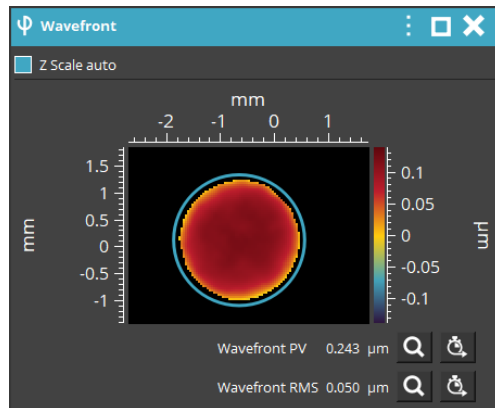


- + No need of coherent light to produce fringes
  - + Take advantage of the reflected signal !
  - + No sample surface preparation

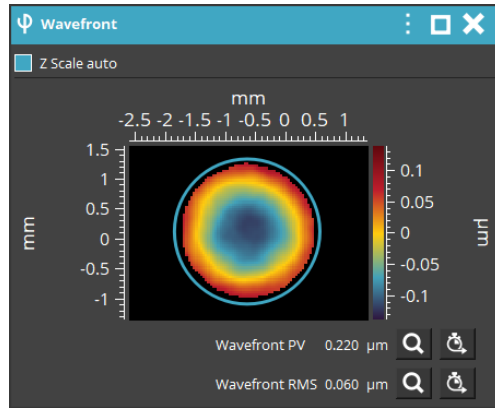
Step 1:  
reflection  
measurement



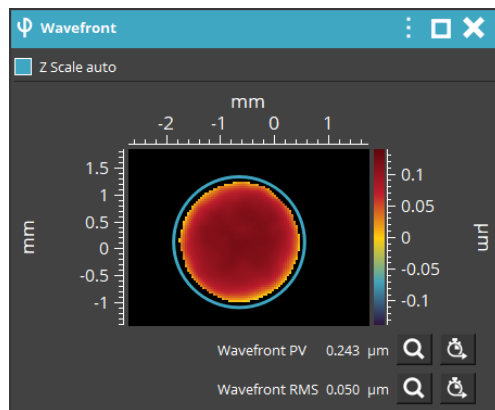
Step 2:  
transmission  
measurement



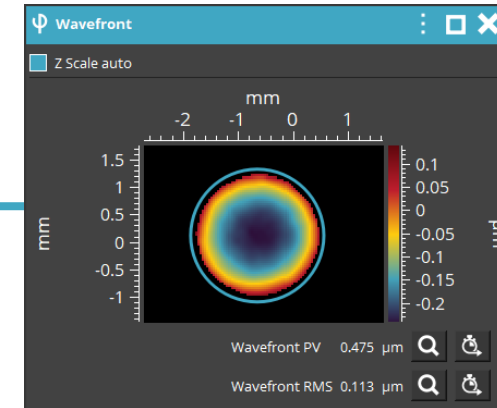
Step 1:  
reflection  
measurement



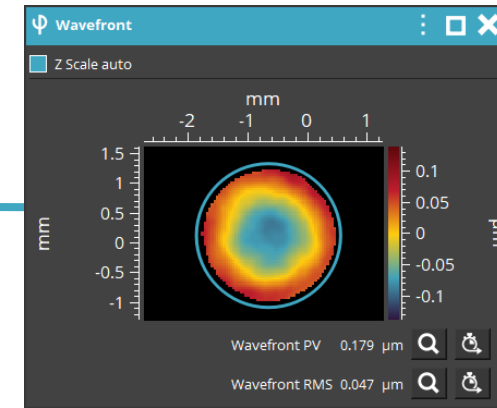
Step 2:  
transmission  
measurement



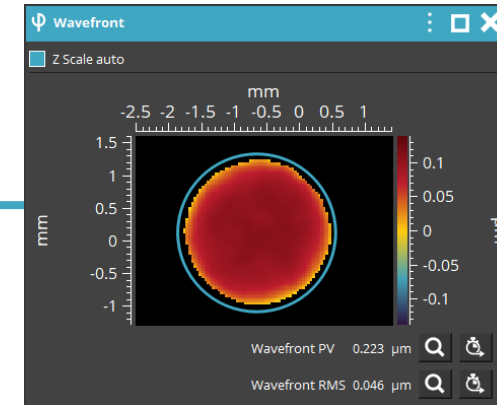
Front surface  
(RWE)



Rear surface  
(RWE)



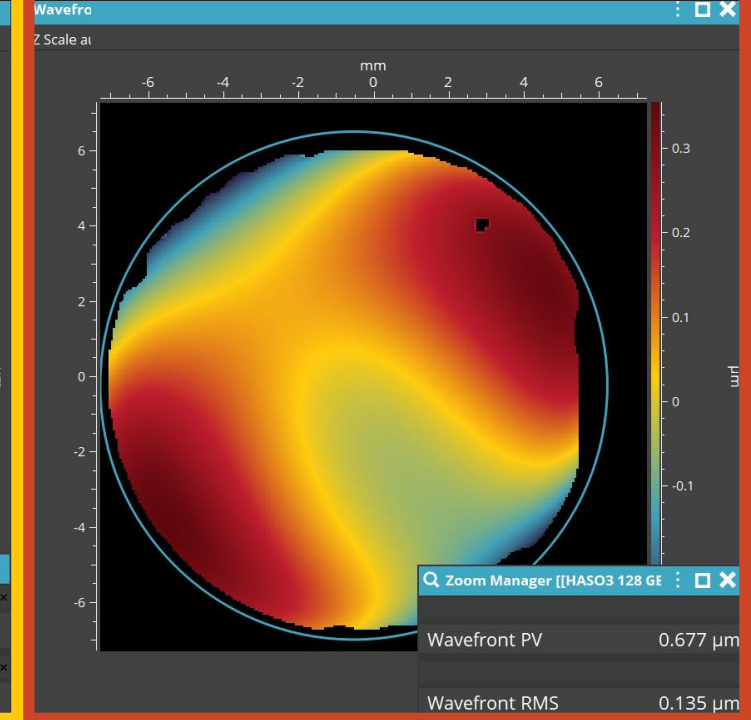
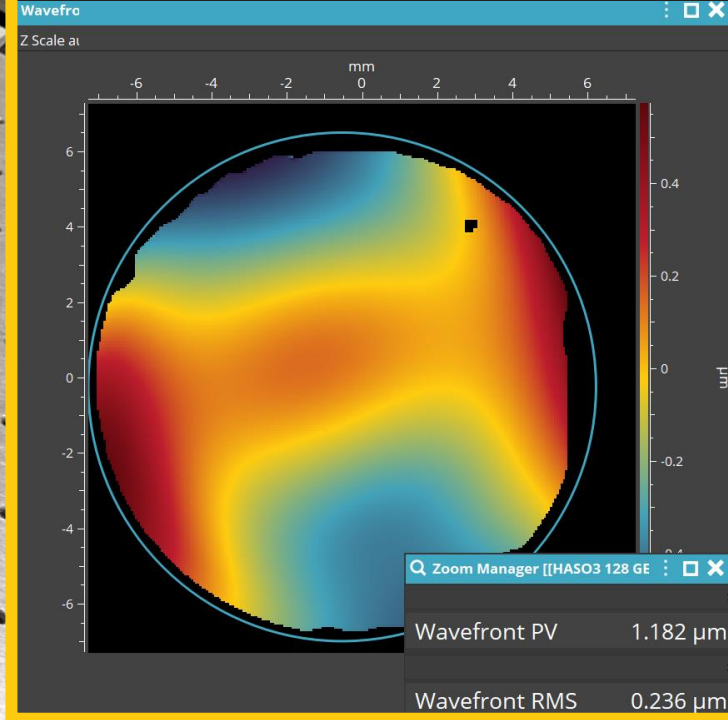
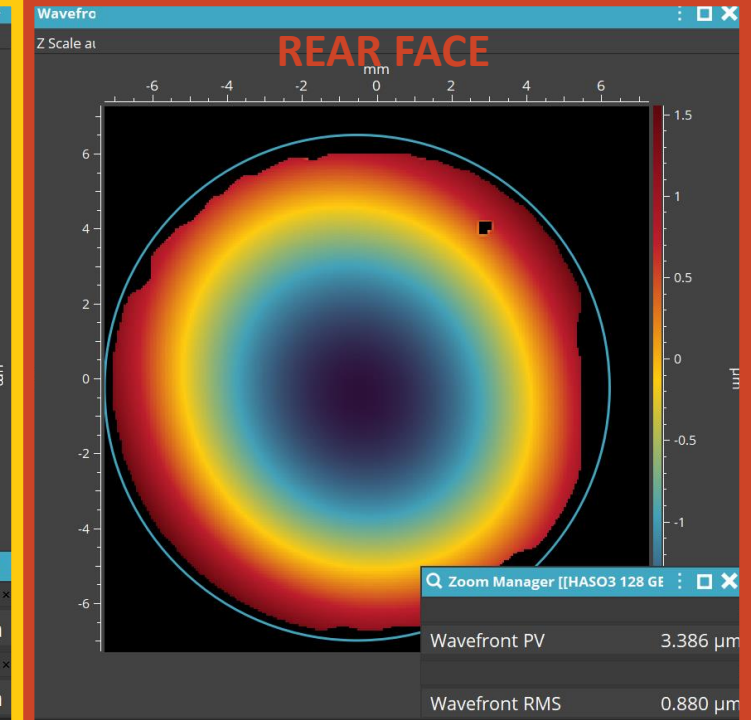
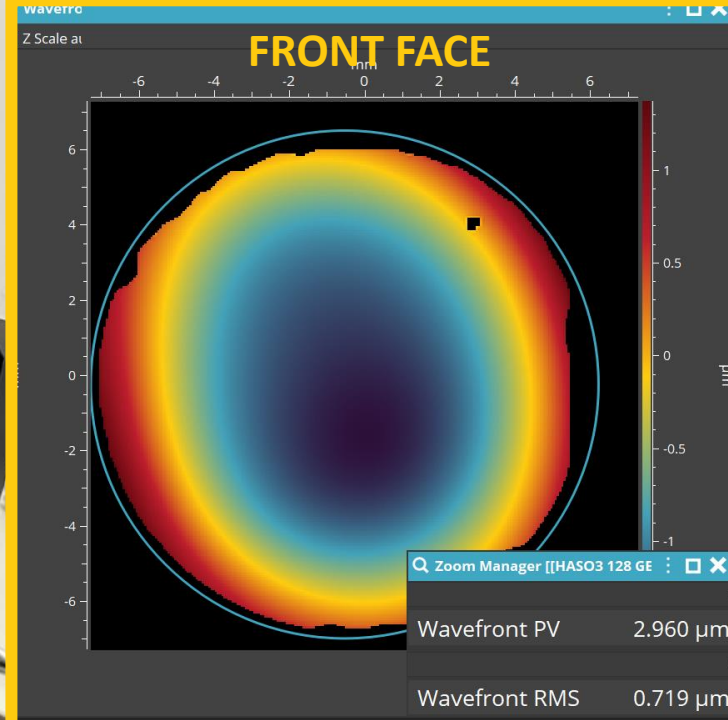
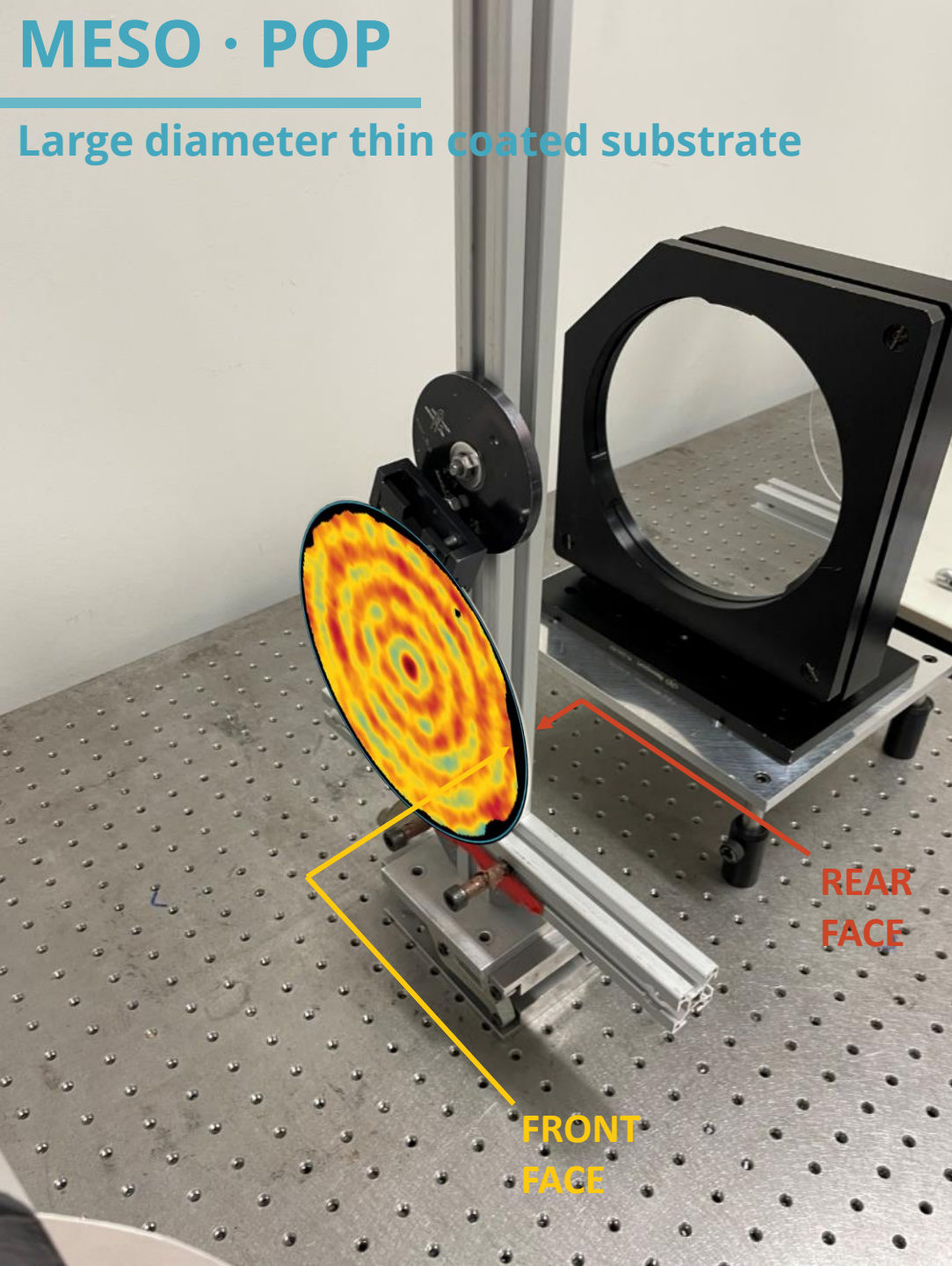
Transmitted  
wavefront (TWE)





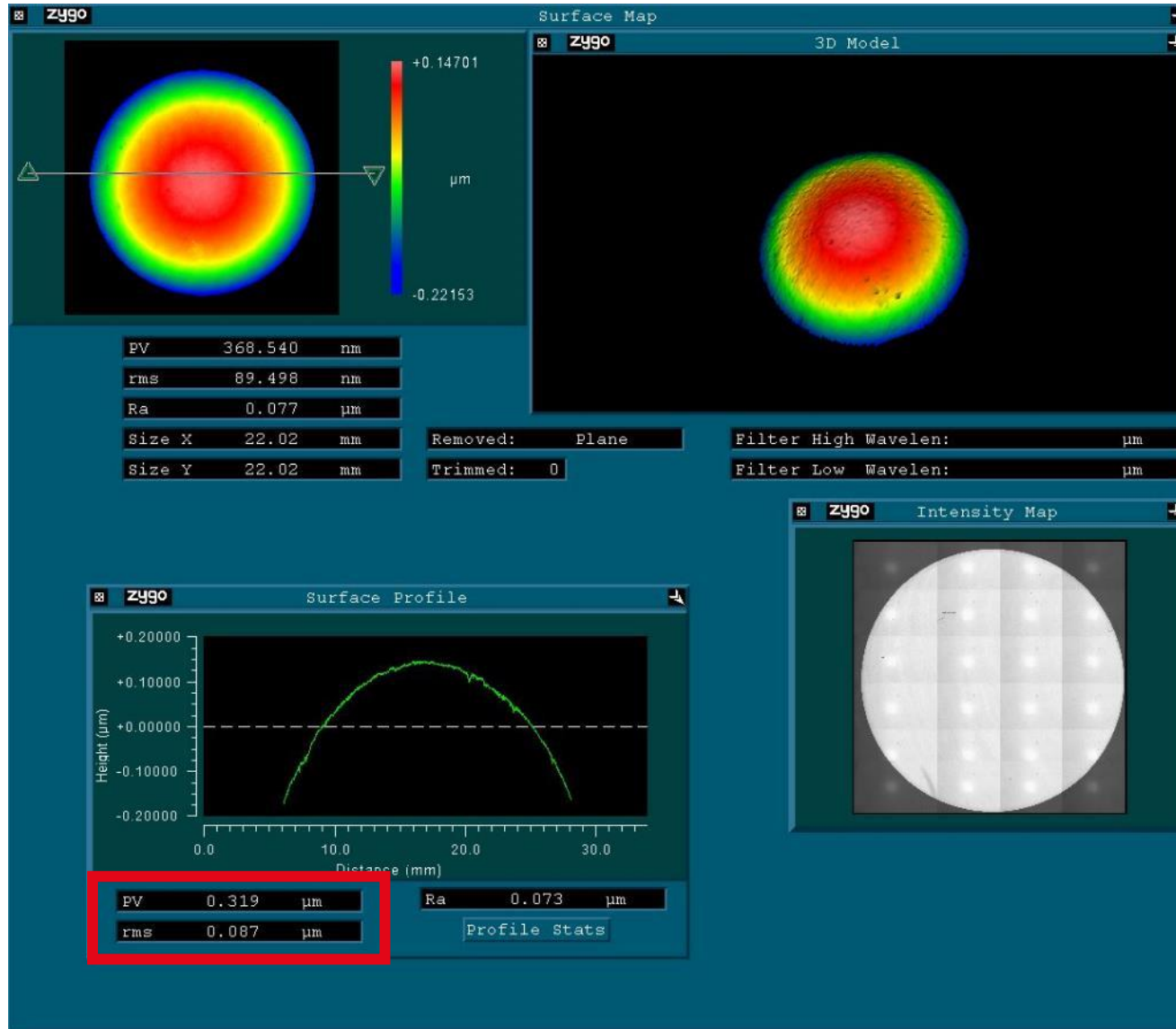
# MESO · POP

Large diameter thin coated substrate

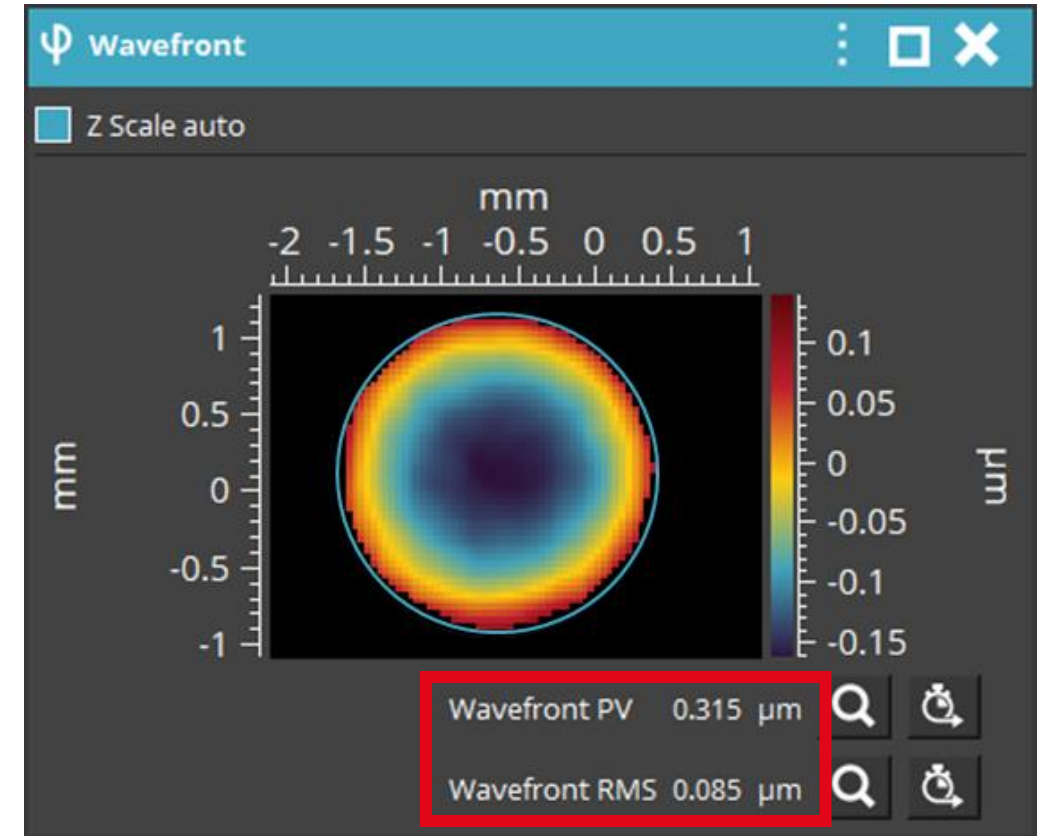


## Flatness of crystal face

White light 3D profilometer : 5 hours



MESO : 1 min.





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Pleased to provide more information  
Happy to perform **tests on your samples**